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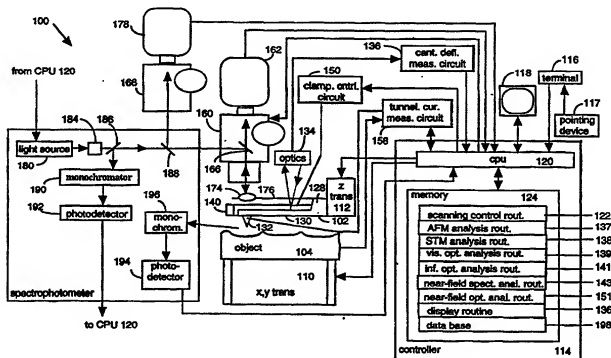
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(54) Title: SCANNING PROBE MICROSCOPE ASSEMBLY



(57) Abstract

A scanning probe microscope assembly (100) is disclosed that has an atomic force measurement (AFM) mode (137), a scanning tunneling measurement (STM) mode (138), a near-field spectrometry mode (143), a near-field optical mode (151), and a hardness testing mode for examining an object (104).